DT06 Rec'd PCT/PTO 0 1 MAR 2005

Sheet 1 of 1

Not yet assigned

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U. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE

LIST OF REFERENCES CITED BY APPLICANT

(Use several sheets if necessary)

CAPEWELL et al

FILING DATE GROUP 2822

March 1, 2005

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BA	AL	"Molecular beam epitaxy of strained Si _{1-x} Ge _x layers on patterned substrates" 1993-06-01, Journal of Crystal Growth, North-Holland Publishing Co., Vol. 130, nos. 3/4, pages 611-616, Bugiel et al.		
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